1st IEEE Latin-American Test Workshop

LATW2000

Marina Palace Hotel
Rio de Janeiro, BRAZIL
March 13-15, 2000

IEEE
IEEE COMPUTER SOCIETY
tttc

www.epo.pucrs.br/~la-tttc/latw00.html

1st IEEE Latin-American Test Workshop

LATW2000

Marina Palace Hotel, Rio de Janeiro, Brazil

March 13 - 15, 2000

Call for Papers

General Chairs:
Fabian Vargas, *PUCRS - Brazil*
vargas@computer.org
Yervant Zorian, *LogicVision - USA*
y.zorian@computer.org

Program Chairs:
Victor Champac, *INAOE - Mexico*
Marcelo S. Lubaszewski, *UFRGS - Brazil*

Publicity Chairs:
Bernard Courtois, *TIMA/INPG - France*
Ingrid Jansch-Porto, *UFRGS - Brazil*

Local Arrangements Chair:
Vladimir Castro Alves, *UFRJ - Brazil*

Brazilian Computer Society Liaison:
Ingrid Jansch-Porto, *UFRGS - Brazil*

Brazilian Microelectronics Society Liaison:
Wilhelmus Van Noije, *USP – Brazil*

Europe Liaison:
J. Paulo Teixeira, *INESC/IST – Portugal*

Asia Liaison:
Kozo Kinoshita, *Osaka Univ. – Japan*

North America Liaison:
Alex Orailoglu, *UC San Diego - USA*

Program Committee:
J. Abraham - *U. of Texas at Austin, USA*
V. D. Agrawal - *Lucent Tech., USA*
E. Barros - *UFPE, Brazil*
B. Bennetts - *Bennetts Assoc., England*
E. A. Bezerra - *PUCRS, Brazil*
A. M. Brochi - *TELEBRAS, Brazil*
O. Calvo - *UNLP, Argentina*
H. Castro - *UFC, Brazil*
S. Demidenko - *Singapore P., Singapore*
R. Duarte - *UFMG, Brazil*
G. Espinosa - *INAOE, Mexico*
A. O. Fernandes - *UFMG, Brazil*
J. Figueras - *UPC, Spain*
J. L. Huertas - *U. of Sevilla, Spain*
A. Ivanov - *UB Columbia, Canada*
B. Kaminska - *OPMAXX, USA*
J. A. Martino - *FEI/FCA-LSI/USP, Brazil*
E. Martins - *UNICAMP, Brazil*
M. Marzouki - *LIP6 Lab., France*
P. C. Maxwell - *Hewlett Packard, USA*
J. V. Medina - *UDV, Colombia*
M. Nicolaidis - *TIMA/INPG, France*
A. R. Paula Jr. - *UNIVAP, Brazil*
D. Pradhan - *Texas A&M U., USA*
P. Prinetto - *Politec. di Torino, Italy*
E. Randon - *USB, Venezuela*
M. Renovell - *LIRMM, France*
A. J. L. Ribeiro - *TELEBRAS, Brazil*
J. M. Santos - *FEUP, Portugal*
M. Sarmiento - *INAOE, Mexico*
M. Strum - *USP, Brazil*
L. E. Toledo - *UCC, Argentina*
R. Velazco - *TIMA/INPG, France*
T. W. Williams - *Synopsys Inc., USA*
H. J. Wunderlich - *U. Stuttgart, Germany*

The 1st IEEE Latin-American Test Workshop provides a forum for specialists from all over the world, especially from Latin America, to present and discuss various aspects of system, board, and component testing with design, manufacturing and field considerations in mind.
The best papers of the workshop will be invited to re-submit to a special issue of the **Journal of Electronic Testing: Theory and Applications, published by Kluwer.**

Topics of interest include, but are not limited to:

- Analog Mixed Signal Test
- Automatic Test Generation/Fault Simulation
- Built-In Self-Test
- Defect & Failure Analysis
- Dependability Estimation
- Distributed Fault-Tolerant Systems
- E-Beam Testing and Thermal Testing
- Economics of Test
- Fault Modeling & Diagnosis
- Fault-Tolerance in Hardware/Software
- Fault-Tolerant Architectures
- Fault-Tolerant Systems Applications
- IDDQ Test
- On-Line Testing
- Process Characterization, Reliability
- Process Control and Measurement
- Simulation and Design Verification
- Software Testing/Software Design for Test
- Synthesis for Testability/Design for Test
- System-on-Chip Test
- Yield Learning and Enhancement

Paper Submission Information:

To encourage and facilitate informal discussions participation will be limited. Those interested in presenting recent results at the workshop please submit four copies of an extended abstract, one to three pages long, or full length paper to one of the Program Chairs below:

Victor Champac
Instituto Nacional de Astrofisica,
Optica y Electronica (INAOE)
Apdo. Postal 51 y 216
Puebla, 72000 Mexico
champac@inaoep.mx

Marcelo Soares Lubaszewski
Universidade Federal do Rio Grande do Sul
Departamento de Engenharia Elétrica
Av. Osvaldo Aranha- Sar. Leite, 103
Porto Alegre, 90035-190 Brazil
luba@iee.ufrgs.br

Authors should include the complete address, phone/fax numbers and e-mail address, and designate a contact person and a presenter. The Program Committee also welcome proposals for panels and special topic sessions. Alternatively, it is strongly encouraged **Post-Script** or **PDF electronic submissions** via the workshop web page:

http://www.epo.pucrs.br/~la-tttc/latw00.html

Submission Deadline: **December 15th, 1999**
Notification of Acceptance: **January 15th, 2000**

Sponsored by:

IEEE Computer Society Test Technology Technical Council (TTTC)

In Cooperation with:

Brazilian Computer Society (SBC), Brazilian Microelectronics Society (SBMicro)
Catholic University (PUCRS), Federal Brazilian Research Agencies CNPq, CAPES
Federal University of RGS (UFRGS), Federal University of Rio de Janeiro (UFRJ).